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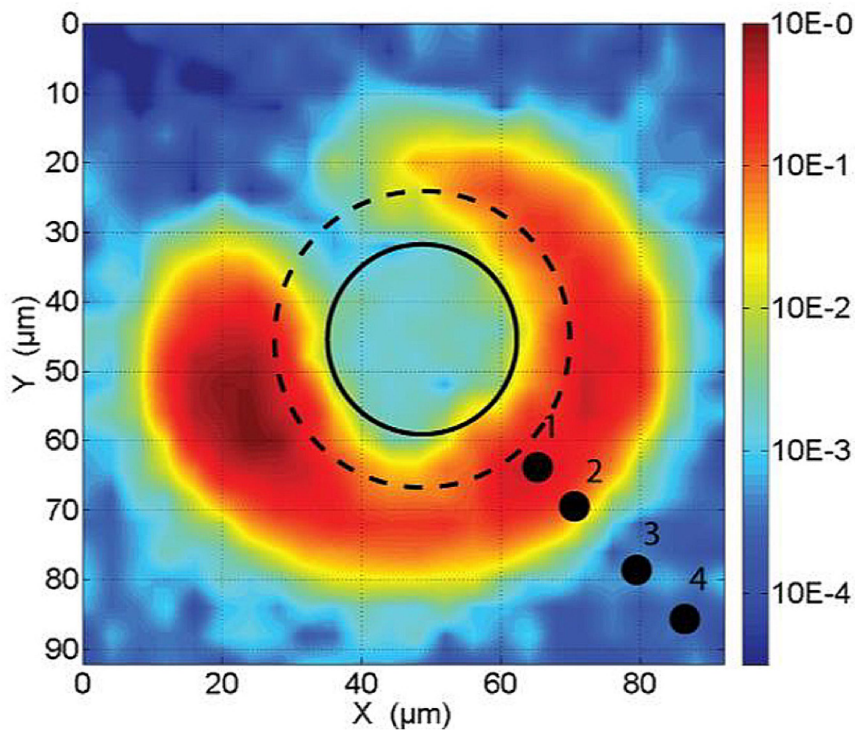
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Normalized maps of spurious counts when scanning the SPAD active area and its periphery with a pulsed laser stimulus before the gate with  $\Delta t = 10$  ns (top) and  $\Delta t = 100$  ns (bottom), respectively. The active area is delimited by a solid line and the edge of the shallow diffusion by the dashed line. The anode metal stripe shields the laser illumination in the top left corner of the figure. Points 1 to 4 are the four spot positions mentioned in legend of Fig. 12 and where the curves therein reported are acquired. Operating conditions:  $V_{EX} = 5$  V,  $V_{UV} = 0.5$  V,  $T_{ON} = 20$  ns,  $T_{OFF} = 100$   $\mu$ s, Temperature = 225 K (Calandri *et al.*, Article #4500107).

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